

<b>Notice of References Cited</b>		Application/Control No. 10/517,377	Applicant(s)/Patent Under Reexamination FURUTA ET AL.	
		Examiner IAN JEN	Art Unit 3664	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-3,655,003 A	04-1972	Yamajima, Kaneo	177/173
*	B	US-5,357,433 A	10-1994	Takenaka et al.	701/23
*	C	US-5,459,659 A	10-1995	Takenaka, Toru	700/260
*	D	US-5,808,433 A	09-1998	Tagami et al.	318/568.12
*	E	US-6,289,265 B1	09-2001	Takenaka et al.	700/245
*	F	US-6,301,524 B1	10-2001	Takenaka, Toru	700/245
*	G	US-6,538,410 B2	03-2003	Mori et al.	318/568.12
*	H	US-2003/0125839 A1	07-2003	Takenaka et al.	700/245
*	I	US-6,832,132 B2	12-2004	Ishida et al.	700/245
*	J	US-6,901,313 B2	05-2005	Mori et al.	700/245
*	K	US-6,898,485 B2	05-2005	Kuroki et al.	700/245
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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